## Supporting Information

# New fused conjugated molecules with fused thiophene and pyran units for organic electronic materials

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#### 1. Experimental section

<sup>1</sup>H NMR and <sup>13</sup>C NMR spectra were recorded on a Bruker Fourier 300, AVANCE III 400 MHz and 500 MHz spectrometers. High resolution mass spectra (HRMS) were determined on Matrix-Assisted Laser Desorption/ Ionization Time of Flight Mass Spectrometry (MALDI-TOF) and electrospray ionization mass spectrometry (ESI-MS). Elemental analysis was performed on a Carlo Erba model 1160 elemental analyzer. TGA-DTA measurements from 30 °C to 600 °C were carried out on a Shimadzu DTG-60 instrument under dry nitrogen flow with a heating rate of 10 °C/min. Jasco V-570 UV-vis spectrophotometer was utilized to measure the solution and thin-film absorption spectra, while a Hitachi (F4500) spectrophotometer was used to record the solution and solid state fluorescence spectra at 25°C. Fluorescence quantum yields and fluorescence lifetimes were measured with a Hamamatsu absolute PL quantum yield spectrometer C11347 Quantaurus QY and the compact fluorescence lifetime spectrometer C11367 of Hamamatsu, respectively. PL images were recorded with an Olympus research inverted system microscope equipped with a CCD camera; a mercury lampequipped with a band pass filter ( $\lambda = 330-380$  nm) was utilized as the excitation source. Cyclic voltammograms were measured on computer controlled CHI660C instruments at room temperature; the measurements were performed in a conventional three-electrode cell using a Pt working electrode, a Pt counter electrode, and a Ag/AgCl (saturated KCl) reference electrode, and *n*-Bu<sub>4</sub>NPF<sub>6</sub> (0.1 M) as the supporting electrolyte with a scan rate of 100 mV·s<sup>-1</sup>. To calibrate the redox potentials, the cyclic voltammogram of ferrocene was measured under the same conditions. Single crystals of TTCTTC and TTTCTTTC was cultivated by slowly cooling their hot solutions in toluene. The diffraction data of single crystals were collected on a Rigaku Saturn diffractometer with a CCD area detector. All calculations were performed with the SHELXS-97 programs. Crystallographic data for the structure reported in this paper were deposited in the Cambridge Crystallographic Data Centre (CCDC: 1963694 for compound TTCTTC, 1975874 for compound TTTCTTTC). X-ray diffraction (XRD) patterns of the thin films were carried out in the reflection mode at room temperature using a 2 kW Rigaku X-ray diffraction system.

#### 2. TGA analysis



Figure S1. TGA curves of TTCTTC and TTTCTTTC from 30-600 °C.

#### 3. X-ray crystallographic data of TTCTTC and TTTCTTTC.

Compound	ТТСТТС	TTTCTTTC
CCDC No.	1963694	1975874
Empirical formula	$C_{38}H_{40}O_2S_4$	$C_{42}H_{40}O_2S_6$
Formula weight	656.94	769.10
Temperature	170.00(11) K	170.00(12) K
Wavelength	0.71073 Å	0.71073 Å
Crystal system, space group	Triclinic, P-1	Triclinic, P-1
Unit cell dimensions	a = 5.34500(10) Å	a = 8.1600(3) Å
	$\alpha = 101.923(2)^{\circ}$	$\alpha = 87.738(3)^{\circ}$
	b = 8.3039(2) Å	b = 8.4682(4)  Å
	$\beta = 93.255(2)^{\circ}$	$\beta = 87.241(3)^{\circ}$
	c = 18.8962(4)  Å	c = 13.9854(5) Å
	$\gamma = 98.322(2)^{\circ}$	$\gamma = 71.942(4)$ °
Volume	808.70(3) Å <sup>3</sup>	916.0(3) Å <sup>3</sup>
Z, Calculated density	1, 1.349 $Mg/m^3$	$1, 1.392 \text{ Mg/m}^3$
Absorption coefficient	2.959 mm <sup>-1</sup>	3.731
F(000)	348	404
Crystal size	0.2 x 0.05 x 0.05 mm <sup>3</sup>	0.23  imes 0.07  imes 0.01
Theta range for data collection	4.798 to 150.886°	6.33 to 151.146°
Limiting indices	-6≤h≤5,	$-10 \le h \le 10$ ,
	-10≤k≤10,	$-8 \le k \le 10,$
	-23 <u>≤</u> 1 <u>≤</u> 23	$-17 \le 1 \le 17$
Reflections collected/unique	9092/3194 [R(int) = 0.0514,	11695/3633 [R <sub>int</sub> = 0.0561, R <sub>sigma</sub>
A has motion as mostion	$R_{sigma} = 0.0489$	= 0.0488
Absorption correction	1 0000 and 0 82621	Semi-empirical from equivalents
Refinement method	Full matrix losst squares on E2	- Full matrix logst squares on F2
Deta / restrainta / norametera	$\Gamma$ un-matrix least-squares on $\Gamma 2$	
Goodness of fit on E2	003971347308	3033/0/228 1.056
	1.031	
Final K indices [I>2sigma(I)]	K1 = 0.0455, WK2 = 0.1057	$R_1 = 0.0897, WR_2 = 0.2433$
K indices (all data)	R1 = 0.0630, wR2 = 0.1185	$R_1 = 0.0992, wR_2 = 0.2565$
Largest diff. peak and hole	0.41 and -0.38 e.Å <sup>-3</sup>	1.26 and -0.55 e.Å <sup>-3</sup>

 Table S1. X-ray crystallographic data of TTCTTC and TTTCTTTC



Figure S2. Molecular structure of TTCTTC.

Table S2. Selected bond lengths of TTCTTC					
Bond lengths from	crystal structure	Bond lengths from the optimized structure			
Atoms 1,2	d 1,2 [Å]	Atoms 1,2	d 1,2 [Å]		
S1-C6	1.741	S1-C6	1.764		
S1-C9	1.733	S1-C9	1.753		
S2-C8	1.719	S2-C8	1.743		
S2-C11	1.752	S2-C11	1.776		
O1-C4	1.398	O1-C4	1.385		
O1-C7	1.370	O1-C7	1.364		
C1-C2	1.374	C1-C2	1.388		
C1-C5a	1.430	C1-C5a	1.434		
C1-C6 <sup>i</sup>	1.447	C1-C6 <sup>i</sup>	1.447		
C2-C3	1.401	C2-C3	1.408		
C3-C4	1.369	C3-C4	1.380		
C4-C5	1.413	C4-C5	1.422		
C5-C5a	1.417	C5-C5a	1.424		
C6-C7	1.368	C6-C7	1.377		
C7-C8	1.411	C7-C8	1.417		
C8-C9	1.385	C8-C9	1.388		
C9-C10	1.423	C9-C10	1.425		
C10-C11	1.361	C10-C11	1.371		



Figure S3. Molecular structure of TTTCTTTC.

Table S3. Selected bond lengths of TTTCTTTC.						
Bond lengths from	crystal structure	Bond lengths from the optimized structure				
Atoms 1,2	Atoms 1,2 d 1,2 [Å]		d 1,2 [Å]			
S1-C7	1.742	S1-C7	1.754			
S1-C8	1.718	S1-C8	1.749			
S2-C9	1.725	S2-C9	1.756			
S2-C10	1.743	S2-C10	1.754			
S3-C11	1.721	S3-C11	1.742			
S3-C12	1.744	S3-C12	1.769			
O1-C5	1.388	O1-C5	1.386			
O1-C6	1.367	O1-C6	1.363			
C1-C2	1.429	C1-C2	1.434			
C1-C5	1.413	C1-C5	1.422			
C2-C3	1.361	C2-C3	1.388			
C3-C4	1.412	C3-C4	1.408			
C1-C1a	1.416	C1-C1a	1.424			
C4-C5	1.369	C4-C5	1.388			
C2-C7	1.454	C2-C7	1.446			
C6-C7	1.358	C6-C7	1.377			
C6-C9	1.419	C6-C9	1.415			
C8-C9	1.388	C8-C9	1.393			
C8-C11	1.430	C8-C11	1.419			
C10-C11	1.375	C10-C11	1.394			
C12-C13	1.368	C12-C13	1.373			

#### 4. DFT calculations



**Figure S4.** Calculated transfer integrals (meV) of **TTCTTC** and **TTTCTTTC** by using the popular long-range functional  $\omega$ B97XD with optimized  $\omega$ =0.00168 and 6-31G(d) basis set.



Figure S5. Energy levels of TTCTTC and TTTCTTTC calculated at PCM-B3LYP/6-31G(d) level.

Table S4. The electronic transitions with transition energy lower than 4.3803 eV	V (280nm) and the oscillator strengths
(f) with their values larger than 0.01 at PCM-B3LYP/6-31G(d) level.	

	ТТСТТС	TTTCTTTC
$S_0 \rightarrow S_2$	2.69 eV (461.1nm) <i>f</i> =0.7906 HOMO→LUMO	2.53 eV (490.9nm) f=1.0733 HOMO→LUMO+1
$S_0 \rightarrow S_3$	3.32 eV (373.9nm) f=0.0917	3.28 eV (378.5nm) f=0.0881

$S_0 \rightarrow S_4$	3.84 eV (323.0nm) f=0.0693	3.55 eV (349.3 nm) f=1.3688 HOMO-1→LUMO
$S_0 \rightarrow S_6$	3.95 eV (313.8nm) ƒ=1.0662 HOMO-1→LUMO+1	3.66 eV (340.1nm) f=0.0062

# 5. Fluorescence spectra of TTCTTC and TTTCTTTC in solutions and solid states



**Figure S6.** Fluorescence spectra of **TTCTTC** and **TTTCTTTC** in solutions (solid line) and solid states (dotted line). **Table S5.** Photoluminescence data of **TTCTTC** and **TTTCTTTC** in solutions and solid states

Compd.	Solution		Solid State			
	PL	$\Phi^{a}$	<\tau>b	PL	$\Phi^{a}$	$< \tau > b$
	$\lambda_{em.}(nm)$	(%)	(ns)	$\lambda_{em.}$ (nm)	(%)	(ns)
TTCTTC	503, 529	13.8	3.56	571	16.5	1.64
ТТТСТТТС	526	13.6	3.35	587	1.5	1.26

[a] The quantum yields in solutions (10  $\mu$ M in CH<sub>2</sub>Cl<sub>2</sub>) and in the solid states were measured with the Hamamatsu spectrometer C11347 Quantaurus-QY. [b] Fluorescence lifetimes in solutions (10  $\mu$ M in CH<sub>2</sub>Cl<sub>2</sub>) and in the solid state were measured with the Hamamatsu spectrometer C11367.

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**Figure S7.** The microscope (a, c) and fluorescence microscope (b, d) ( $\lambda_{ex} = 330-380$  nm) images of **TTCTTC** and **TTTCTTTC** crystals, respectively.

#### 6. ESR spectra of TTCTTC and TTTCTTTC in the presence of CF<sub>3</sub>COOH



**Figure S8.** ESR spectra of  $CH_2Cl_2$  solution of **TTCTTC** and **TTTCTTTC** in the presence of 1%wt TFA (CF<sub>3</sub>COOH).

7. UV-vis-NIR spectra of TTCTTC and TTTCTTTC after electrochemical oxidation



**Figure S9.** The UV-vis-NIR spectra of solutions of **TTCTTC** (a, 10  $\mu$ M) and **TTTCTTTC** (b, 10  $\mu$ M) after electrochemical oxidation. The spectroelectrochemical experiments were carried out in 1 mm spectroelectrochemical cell containing platinum minigrid working electrode, Pt counter electrode and Ag/AgCl reference electrode. The spectra were recorded after the solutions were applied an oxidation potential at +0.6 V (vs Ag/AgCl) for 30 min.

8. Transfer and output curves of OFETs with thin films of TTCTTC and TTTCTTTC



**Figure S10.** Transfer (a, b and c) and output (d, e and f) characteristics of OFETs with thin films of **TTCTTC** deposited on OTS-modified SiO<sub>2</sub>/Si substrate at 25 °C (a and d), 50 °C (b and e) and 90 °C (c and f).



**Figure S11.** Transfer (a, b and c) and output (d, e and f) characteristics of OFETs with thin films of **TTTCTTTC** deposited on OTS-modified SiO<sub>2</sub>/Si substrate at 25 °C (a and d), 50 °C (b and e) and 90 °C (c and f).

Compd.	Substrate temp. (°C)	$\mu_{max} \ [cm^2 V^{-1} s^{-1}]$	$\begin{array}{c} \mu_{average}{}^a \\ [cm^2  V^{\text{-1}}  s^{\text{-1}}] \end{array}$	On/off ratio	Threshold (V)
TTCTTC	90	0.26	0.20	1x10 <sup>7</sup>	10 V
	50	0.39	0.25	2x10 <sup>7</sup>	13 V
	25	0.31	0.19	1x10 <sup>7</sup>	9 V
TTTCTTTC	90	0.031	0.017	2x10 <sup>7</sup>	7 V
	50	0.025	0.013	2x10 <sup>7</sup>	2 V
	25	0.016	0.008	5x10 <sup>7</sup>	3 V

Table S6. The performance data for OFETs with thin films of TTCTTC and TTTCTTTC

[a] based on 10 devices

# 9. XRD patterns of TTCTTC and TTTCTTTC films deposited at different temperatures



**Figure S12.** XRD patterns of thin-films of **TTCTTC** (a) and **TTTCTTTC** (b) deposited on OTS-modified SiO<sub>2</sub>/Si substrates at different temperatures (a, 25 °C; b, 50 °C; c, 90 °C).

#### 10. AFM images of TTCTTC deposited at different temperatures



**Figure S13.** AFM height images of thin-films of **TTCTTC** deposited on OTS-modified SiO<sub>2</sub>/Si substrates at different temperatures (a, 25 °C; b, 50 °C; c, 90 °C).

#### 11. AFM images of TTTCTTTC deposited at different temperatures



**Figure S14.** AFM height images of thin-films of **TTTCTTTC** deposited on OTS-modified SiO<sub>2</sub>/Si substrates at different temperatures (a, 25 °C; b, 50 °C; c, 90 °C).

#### 12. References

[1] Gaussian 09, Revision A.02, M. J. Frisch, G. W. Trucks, H. B. Schlegel, G. E. Scuseria, M. A. Robb, J. R. Cheeseman, G. Scalmani, V. Barone, B. Mennucci, G. A. Petersson, H. Nakatsuji, M. Caricato, X. Li, H. P. Hratchian, A. F. Izmaylov, J. Bloino, G. Zheng, J. L. Sonnenberg, M. Hada, M. Ehara, K. Toyota, R. Fukuda, J. Hasegawa, M. Ishida, T. Nakajima, Y. Honda, O. Kitao, H. Nakai, T. Vreven, J. A. Montgomery, Jr., J. E. Peralta, F. Ogliaro, M. Bearpark, J. J. Heyd, E. Brothers, K. N. Kudin, V. N. Staroverov, R. Kobayashi, J. Normand, K. Raghavachari, A. Rendell, J. C. Burant, S. S. Iyengar, J. Tomasi, M. Cossi, N. Rega, J. M. Millam, M. Klene, J. E. Knox, J. B. Cross, V. Bakken, C. Adamo, J. Jaramillo, R. Gomperts, R. E. Stratmann, O. Yazyev, A. J. Austin, R. Cammi, C. Pomelli, J. W. Ochterski, R. L. Martin, K. Morokuma, V. G. Zakrzewski, G. A. Voth, P. Salvador, J. J. Dannenberg, S. Dapprich, A. D. Daniels, O. Farkas, J. B. Foresman, J. V. Ortiz, J. Cioslowski, and D. J. Fox, Gaussian, Inc., Wallingford CT, 2009.

#### 13. NMR Spectra.



160 150 140 130 120 110 100 90 80 70 60 50 40 30 20 10 0 -10 f1 (ppm) Figure S16. <sup>13</sup>C NMR spectrum of **3a** in CDCl<sub>3</sub> (25°C).



### -3.62 - 3.62 -







**Figure S18.** <sup>13</sup>C NMR spectrum of **3b** in  $[D_8]$ THF (25°C).







Figure S22. <sup>13</sup>C NMR spectrum of 4a in CDCl<sub>3</sub> (25°C).

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